

<b>Notice of References Cited</b>	Application/Control No. 10/509,455	Applicant(s)/Patent Under Reexamination VAN DEN OETELAAR, RONALD	
	Examiner Henok G. Heyi	Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,932,301 A	08-1999	Kamiyama et al.	427/558
*	B	US-6,190,750 B1	02-2001	Wierenga et al.	428/64.1
*	C	US-2001/0005350 A1	06-2001	Kitaura et al.	369/94
*	D	US-2001/0016242 A1	08-2001	Miyamoto et al.	428/64.4
*	E	US-2002/0018870 A1	02-2002	Meinders et al.	428/64.4
*	F	US-2002/0024913 A1	02-2002	Kojima et al.	369/94
*	G	US-2005/0254407 A1	11-2005	Hwang et al.	369/275.1
*	H	US-2006/0109577 A1	05-2006	Mijiritskii, Andrei	359/883
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.